

# Search Notes



Application/Control No.

09/703,792

Examiner

CHUONG T. HO

Applicant(s)/Patent under Reexamination

HAYAKAWA ET AL.

Art Unit

2616

## SEARCHED

Class	Subclass	Date	Examiner
370	230	09/25/06	CH
↓	229		
↓	231		
↓	232		
370	234		
↓	235		
↓	235.1		
↓	236.1		
↓	412		
↓	414		
↓	415		
↓	416		
↓	417		
↓	418		
↓	428		
↓	429		
↓	503		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
WEST (Text search, class search)	09/25/06	CH
EAST	↓	↓
STN		
IEEE		

[illegible]

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[illegible]

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

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